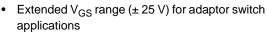


# P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$ Max.	I <sub>D</sub> <sup>a</sup>	Q <sub>g</sub> (Typ.)		
	0.0080 at V <sub>GS</sub> = - 10 V	- 60			
- 30	0.0090 at V <sub>GS</sub> = - 6 V	- 53	66 nC		
	0.0012 at V <sub>GS</sub> = - 4.5 V	- 50			

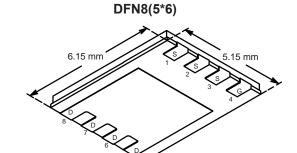
#### **FEATURES**

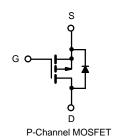




RoHS

- Extremely low R<sub>DS(on)</sub>
- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested
- Typical ESD Performance: 4000 V (HBM)





Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	- 30	V		
Gate-Source Voltage		V <sub>GS</sub>	± 20	V	
	T <sub>C</sub> = 25 °C		- 60		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 70 °C	] [	- 50.7		
Continuous Diam Curient (1) = 130 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	- 47.3		
	T <sub>A</sub> = 70 °C		- 43.9 <sup>b, c</sup>	Α	
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub>	- 150	^	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I-	- 58 <sup>b, c</sup>		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	- I <sub>S</sub> -	- 46 <sup>b, c</sup>		
Single Pulse Avalanche Current	1 0.1 ml l	I <sub>AS</sub>	- 40		
Single Pulse Avalanche Energy  L = 0.1 mH		E <sub>AS</sub>	80	mJ	
	T <sub>C</sub> = 25 °C		75		
Mayimum Dawar Dissination	T <sub>C</sub> = 70 °C	$\begin{bmatrix} \\ P_D \end{bmatrix}$	40	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	] <sup>FD</sup> [	3.1 <sup>b, c·</sup>	VV	
	T <sub>A</sub> = 70 °C		2 <sup>b, c</sup>		
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	33	40	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	15	17	0, **		

#### Notes:

- a. Based on  $T_C = 25$  °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under steady state conditions is 90 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static				<u>'</u>		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V
$V_{DS}$ Temperature Coefficient $\Delta V_{DS}$		$V_{DS}/T_{J}$		- 24		1400
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = - 250 μA		6		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_{D} = -250 \mu A$	- 1.0		- 2.5	V
0.10		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 150	- μΑ
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 15	
		V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V			- 1	
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> ≤ - 5 V, V <sub>GS</sub> = - 10 V	- 20			Α
	(- /	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 13 A		0.0080		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 6 V, I <sub>D</sub> = - 10 A		0.0090		
	(,	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 8 A		0.0120		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 13 A		44		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			4620		pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		880		
Reverse Transfer Capacitance	C <sub>rss</sub>			820		
Total Cata Charms	0	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 17.3 A		102	153	
Total Gate Charge	Q <sub>g</sub>			66	80	nC
Gate-Source Charge		V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 5 V, I <sub>D</sub> = - 17.3 A		16		
Gate-Drain Charge	$Q_{gd}$			28		
Gate Resistance	$R_g$	f = 1 MHz	0.3	1.3	2.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			70	105	
Rise Time	t <sub>r</sub>	$V_{DD} = 0 \text{ V}, R_L = 1.5 \Omega$		70	105	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 10 A, $V_{GEN}$ = - 4.5 V, $R_g$ = 1 $\Omega$		45	68	1
Fall Time	t <sub>f</sub>			27	41	1
Turn-On Delay Time	t <sub>d(on)</sub>			18	30	ns
Rise Time	t <sub>r</sub>	$V_{DD} = -15 \text{ V}, R_{L} = 1.5 \Omega$		15	25	- - -
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 10 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		52	80	
Fall Time	t <sub>f</sub>			14	25	
<b>Drain-Source Body Diode Characteristic</b>	s			<b>'</b>		
Continuous Source-Drain Diode Current I <sub>S</sub>		T <sub>C</sub> = 25 °C			- 5.8	A
Pulse Diode Forward Current I <sub>SM</sub>					- 60	^
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 10 A, V <sub>GS</sub> = 0 V		- 0.78	- 1.2	V
Body Diode Reverse Recovery Time t <sub>rr</sub>				35	53	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	L 10 A dl/dt _ 100 A/vo T _ 25 °C		25	38	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		19		
Reverse Recovery Rise Time	t <sub>b</sub>			16		ns

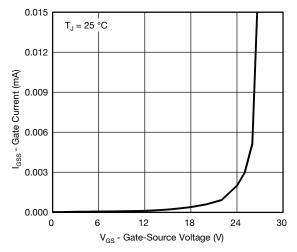
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

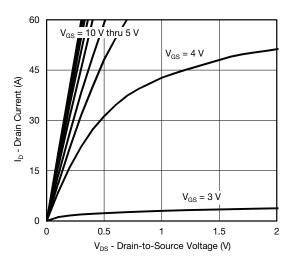
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



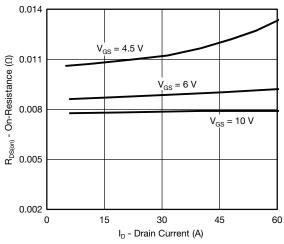
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



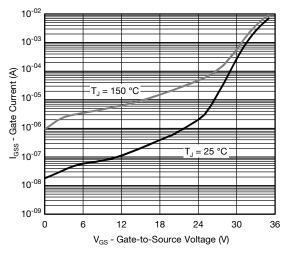
Gate Current vs. Gate-Source Voltage



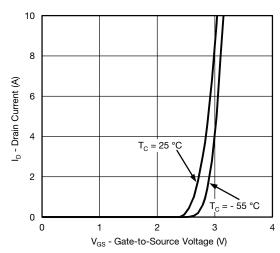
**Output Characteristics** 



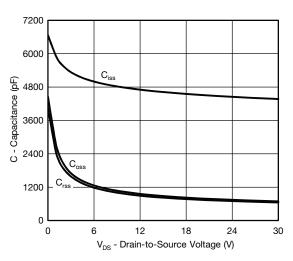
On-Resistance vs. Drain Current



Gate Current vs. Gate-Source Voltage



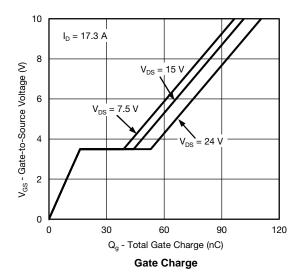
**Transfer Characteristics** 

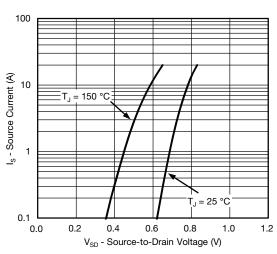


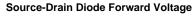
Capacitance

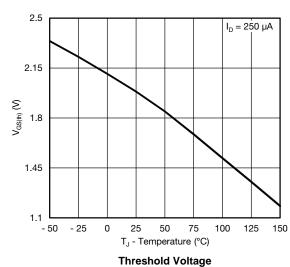


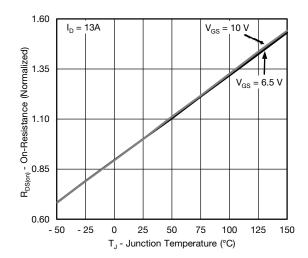
## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



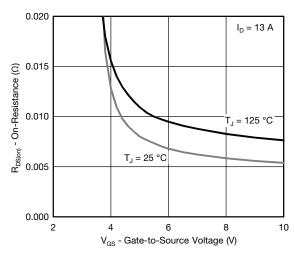




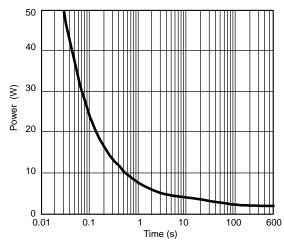




On-Resistance vs. Junction Temperature



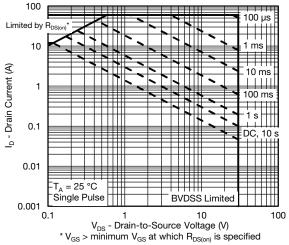
On-Resistance vs. Gate-to-Source Voltage



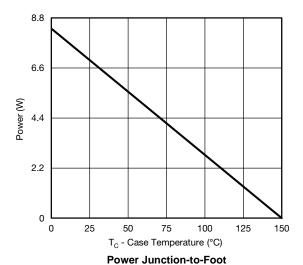
Single Pulse Power, Junction-to-Ambient

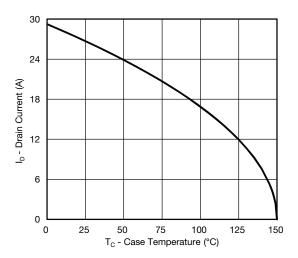


### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

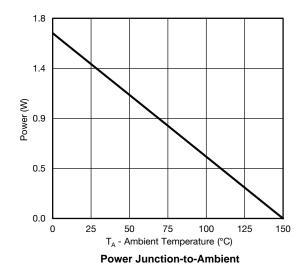








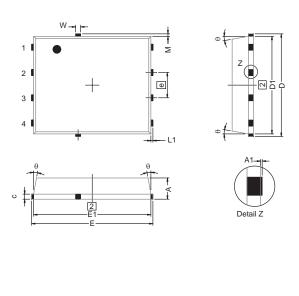


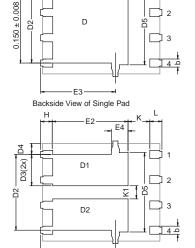


<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



# PowerPAK SO-8, (SINGLE/DUAL)





#### Notes

- 1. Inch will govern.
- 2 Dimensions exclusive of mold gate burrs.
- 3. Dimensions exclusive of mold flash and cutting burrs.

Backside	View	of	Dual	Pad

		MILLIMETERS		INCHES			
DIM.	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	0.97	1.04	1.12	0.038	0.041	0.044	
A1	0.00	-	0.05	0.000	-	0.002	
b	0.33	0.41	0.51	0.013	0.016	0.020	
С	0.23	0.28	0.33	0.009	0.011	0.013	
D	5.05	5.15	5.26	0.199	0.203	0.207	
D1	4.80	4.90	5.00	0.189	0.193	0.197	
D2	3.56	3.76	3.91	0.140	0.148	0.154	
D3	1.32	1.50	1.68	0.052	0.059	0.066	
D4		0.57 TYP.		0.0225 TYP.			
D5		3.98 TYP.		0.157 TYP.			
E	6.05	6.15	6.25	0.238	0.242	0.246	
E1	5.79	5.89	5.99	0.228	0.232	0.236	
E2	3.48	3.66	3.84	0.137	0.144	0.151	
E3	3.68	3.78	3.91	0.145	0.149	0.154	
E4		0.75 TYP.		0.030 TYP.			
е		1.27 BSC		0.050 BSC			
K	1.27 TYP.				0.050 TYP.		
K1	0.56	-	-	0.022	-	-	
Н	0.51	0.61	0.71	0.020	0.024	0.028	
L	0.51	0.61	0.71	0.020	0.024	0.028	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
θ	0°	-	12°	0°	-	12°	
W	0.15	0.25	0.36	0.006	0.010	0.014	
M	0.125 TYP. 0.005 TYP.				•		

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DWG: 5881



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